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### DOCTEUR EN SCIENCES

#### TOF-SIMS molecular depth profiling of polymers and organic materials using low energy atomic primary ions for sputtering

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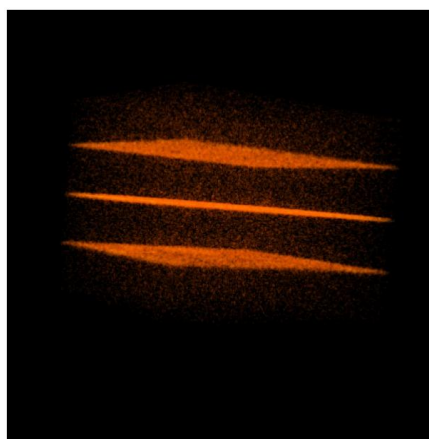
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## **ToF-SIMS molecular depth profiling of polymers and organic materials using low energy atomic primary ions for sputtering**

(Profilage moléculaire de polymères et de matériaux organiques en ToF-SIMS à l'aide d'ions primaires atomiques de basse énergie pour l'érosion.)



Thèse présentée par  
Nicolas Mine  
en vue de l'obtention  
du grade de Docteur en Sciences

**Faculté des Sciences**

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